### QUADRUPLE 2-INPUT POSITIVE-NAND GATES WITH OPEN-COLLECTOR OUTPUTS

APRIL 1985 - REVISED MARCH 1988

- Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers and Flat Packages, and Plastic and Ceramic DIPs
- Dependable Texas Instruments Quality and Reliability

#### description

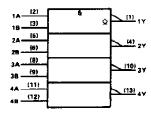
These devices contain four independent 2-input NAND gates. The open-collector outputs require pull-up resistors to perform correctly. They may be connected to other open-collector outputs to implement active-low wired-OR or active-high wired-AND functions. Open-collector devices are often used to generate higher VOH levels.

The SN5401 and SN54LS01 are characterized for operation over the full military temperature range of -55°C to 125°C. The SN7401 and SN74LS01 are characterized for operation from 0°C to 70°C.

#### **FUNCTION TABLE (each gate)**

INPL	JTS	OUTPUT
A	В	Υ
Н	Н	L
L	Х	[ н
×	L	н

#### logic symbol†



<sup>&</sup>lt;sup>†</sup>This symbol is in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12.

Pin numbers shown are for D, J, N, and W packages.

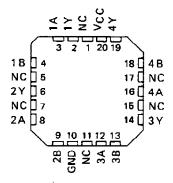
SN5401 . . . J PACKAGE SN54LS01 . . . J OR W PACKAGE SN7401 . . . N PACKAGE SN74LS01 . . . D OR N PACKAGE (TOP VIEW)

1Y	Πī	U14 Vcc
1A	$\square$ 2	13 4 Y
1B	□3	12 🗆 4 B
2Y	□4	11 AA
2A	₫5	10 3Y
2B	□6	9∐ 3B
GND	□ 7	8 🗖 3A

# SN5401 . . , W PACKAGE (TOP VIEW)

1 A	ďι	U 14] 4 Y
1 B	$\square^2$	13 🗀 4 B
1 Y	□3	12 AA
۷сс	□4	סאם ⊈יו
2 Y	□5	10 <b>□ 3 B</b>
2A	<b>[</b> 6	9 🗖 3 A
2 B	□7	8 🗖 3 Ƴ

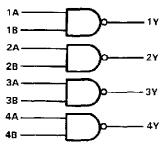
# SN54LS01 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

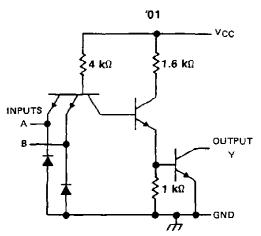
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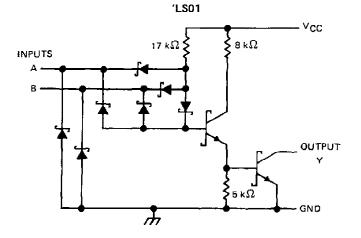
### logic diagram (positive logic)



positive logic;  $Y = \overline{A \cdot B}$  or  $Y = \overline{A} + \overline{B}$ 

#### schematics (each gate)





Resistor values shown are nominal.

## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, VCC (see Note 1): '0	D1, 'LS01 7	7 V
	5.5	
'LS01	. ,	/ V
Off-state output voltage		' V
Operating free-air temperature range:	SN54' ~55°C to 125	°C
	SN74'	°C
Storage temperature range	65°C to 150	°C

NOTE 1: Voltage values are with respect to network ground terminals.

### SN5401, SN7401 QUADRUPLE 2-INPUT POSITIVE-NAND GATES WITH OPEN-COLLECTOR OUTPUTS

#### recommended operating conditions

			SN5401			SN7401			
		MIN	NOM	MAX	MIN	NOM	МАХ	UNIT	
Vcc	Supply voltage	4.5	5	5.5	4.75	5	5.25	V	
ViH	High-level input voltage	2			2			٧	
VIL	Low-level input voltage			0.8			8.0	V	
۷он	High-level output voltage			5.5		_	5,5	ν	
loL	Low-level output current			16			16	mΑ	
Тд	Operating free-air temperature	- 55		125	0		70	°C	

#### electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETER	TEST CONDITIONS <sup>†</sup>	SN5401	SN7401	
PARAMETER	TEST CONDITIONS.	MIN TYP# MAX	MIN TYP <sup>‡</sup> MAX	UNIT
Vıĸ	V <sub>CC</sub> = MIN, I <sub>I</sub> = -12 mA	- 1.5	<b>–</b> 1.5	V
7	VCC = MIN, VIL = 0.8 V, VOH = 5.5 V		0.25	_^
Іон	VCC = MIN, VIL = 0.7 V, VOH = 5.5 V	0.25		mΑ
V <sub>OL</sub>	V <sub>CC</sub> = MIN, V <sub>IH</sub> = 2 V, I <sub>OL</sub> = 16 mA	0.2 0.4	0.2 0.4	V
4	VCC = MAX, VI = 5.5 V	1	1	mA
lн	V <sub>CC</sub> = MAX. V <sub>I</sub> = 2.4 V	40	40	μΑ
ΠL	V <sub>CC</sub> = MAX, V <sub>I</sub> = 0.4 V	-1.6	-1.6	mA
Іссн	$V_{CC} = MAX, V_I = 0$	4 8	4 8	mA
<sup>I</sup> CCL	$V_{CC} = MAX$ , $V_{\parallel} = 4.5 \text{ V}$	12 22	12 22	mA

 $<sup>^{\</sup>dagger}$ For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.  $^{\ddagger}$ All typical values are at V<sub>CC</sub>  $^{\ddagger}$  5 V, T<sub>A</sub>  $^{\ddagger}$  25 °C.

## switching characteristics, VCC = 5 V, TA = 25°C (see note 2)

PARAMETER	FROM (INPUT)	<b>T</b> O (OUTPUT)	TEST CONDITIONS		MIN T	YP M	IAX	UNIT
₹PLH	A or B	V	RL=4kΩ,	CL = 15 pF		35	55	ns
tPHL	7,010	j	R <sub>L</sub> = 400 Ω,	CL = 15 pF		8	15	ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.

## SN54LS01, SN74LS01 QUADRUPLE 2-INPUT POSITIVE-NAND GATES WITH OPEN-COLLECTOR OUTPUTS

#### recommended operating conditions

		SN54LS01			SN74LS01			
	MIN	NOM	MAX	MIN	NOM	MAX	UNIT	
V <sub>CC</sub> Supply voltage	4,5	5	5.5	4.75	5	5.25	٧	
VIH High-level input voltage	2			2	_		V	
VIL Low-level input voltage			0.7			0.8	V	
VOH High-level output voltage			5. <del>5</del>			5.5	V	
IOL Low-level output current			4	-		8	mА	
TA Operating free-air temperature	- 55		125	0		70	°c	

## electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS †		SN54LS01			SN74LS01				
PARAWE   ER	ļ	1E\$1 CONDI	TIONS	MIN	TYP‡	MAX	MIN	TYP#	MAX	UNIT
Vik	V <sub>CC</sub> - MIN,	I <sub>I</sub> = ~ 18 mA	<del></del>			- 1.5			- 1.5	V
10н	V <sub>CC</sub> = MIN,	V <sub>IL</sub> = MAX,	V <sub>OH</sub> = 5.5 ∨			0.1			0.1	mΑ
14	VCC = MIN,	V <sub>IH</sub> = 2 V,	IOL = 4 mA		0.25	0.4		0.25	0.4	V
VOL	V <sub>CC</sub> = MIN,	V <sub>IH</sub> = 2 V,	IOL = 8 mA					0.35	0.5	'
41	VCC = MAX.	V <sub>I</sub> = 7 V				0.1			0.1	mA
<sup>†</sup> IH	V <sub>CC</sub> = MAX,	V <sub>1</sub> = 2.7 V			_	20			20	μА
412	V <sub>CC</sub> = MAX,	V <sub>1</sub> = 0.4 V	···			- 0.4			- 0.4	mA
ГССН	VCC = MAX,	V <sub>I</sub> = 0	<del></del>		0.8	1.6	i	0.8	1.6	mΑ
1 <sub>CC</sub> L	V <sub>CC</sub> = MAX,	V <sub>1</sub> = 4.5 V			2.4	4.4		2.4	4.4	mA

<sup>†</sup> For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

## switching characteristics, $V_{CC} = 5 \text{ V}$ , $T_A = 25^{\circ}\text{C}$ (see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS		MIN	TYP	MAX	UNIT
tPLH	A or B	Y	R. = 2k0	CL = 15 pF		17	32	ns
<sup>‡</sup> PHL	,,,,,,	·	R <sub>L</sub> = 2 kΩ,	C[ - 13 pr		15	28	ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.

<sup>‡</sup> All typical values are at  $V_{CC}$  = 5 V,  $T_A$  = 25°C.

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